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The large element map (4076 x 3072 pixels, 110 nm pixel size) was acquired with an annular XFlash<sup>®</sup> silicon drift detector. The SDD is inserted between the pole piece and the sample, and ideally suited for the analysis of topographically complex samples. Shadowing effects are minimized by collecting X-rays using four separate detector segments. A low accelerating voltage of 3 kV and a low beam current of 220 pA was applied to examine the fine structure of the beam sensitive sample at the sub-µm scale. These conditions produced an input count rate of 27 kcps due to the large solid angle of 1.1 sr. Sample courtesy: D. P. S. Dalto, M. J. O. C. Guimarães, M. E. F. Garcia, UFRJ/Rio de Janeiro, Brazil.

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